

Notice of References Cited	Application/Control No. 10/575,341		Applicant(s)/Patent Under Reexamination STICH ET AL.	
	Examiner ISAAC T. TECKLU		Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0200149	10-2003	Gonzalez et al.	705/26
*	B	US-2002/0147974	10-2002	Wookey, Michael J.	717/176
*	C	US-6,301,708	10-2001	Gazdik et al.	717/175
*	D	US-7,409,685	08-2008	Chen et al.	717/170
*	E	US-6,725,452	04-2004	Te'eni et al.	717/168
*	F	US-6,912,543	06-2005	Agulhon, Isabelle	1/1
*	G	US-5,761,380 A	06-1998	Lewis et al.	706/47
*	H	US-2004/0113945 A1	06-2004	Park et al.	345/765
*	I	US-6,282,711 B1	08-2001	Halpern et al.	717/175
*	J	US-5,870,611 A	02-1999	London Shrader et al.	717/175
*	K	US-2003/0200356 A1	10-2003	Hue, Vincent	709/322
*	L	US-2003/0159130 A1	08-2003	Broussard et al.	717/120
*	M	US-2003/0018964 A1	01-2003	Fox et al.	717/177

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.